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Introduction

Photonics Asia met in Beijing, China during the week of 11–15 of November 2007.

By all indications it was a rousing success. Photonics Asia opened the conference with a memorable opening ceremony with SPIE leaders introduced from throughout the world, followed by four Plenary speeches:

- Solid State Lighting
by Jinmin Li of the Institute of Semiconductors of the Chinese Academy of Science
- The National Ignition Facility also known as the World's Largest Optical System
by Christopher Stolz of Lawrence Livermore National Laboratory in the USA
- A Brief Introduction to Biophotonics and Selected Applications
by Arthur Chiou of the National Yang-Ming University in Japan
- Terahertz Wave Photonics in Gas and its Spectroscopic Applications
by X.-C. Zhang of the Rensselaer Polytechnic Institute in the USA

Photonics Asia started as a new conference in 2002 in Shanghai, followed by a second conference held also in Beijing in 2004. This 3rd Photonics Asia (2007) was managed and sponsored by SPIE and the Chinese Optical Society (COS). Many corporation leaders participated in the conference.

Attendance at the conference has been growing reaching a total over the entire conference of 1269 papers, 615 posters, and 127 invited talks, including a strong international presence this year. The conference topics within the Optical Design and Testing conference span a wide variety of fields including

- Astronomical and space optics
- Wavefront sensing and coding
- Novel system design
- Illumination system design
- Compact optics
- Head-mounted display design
- Nano- and Micro-optics
- Optical system analysis and optimization
- Optical Measurement
- Optical testing and system alignment
- Testing for aspheric surfaces
- Interferometry in optical testing

It was a pleasure working with SPIE and Photonics Asia 2007, and we look forward to seeing you in 2009!

Yongtian Wang
Theo T. Tschudi
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